


Issue Classification 	Application/Control No.		Applicant(s)/Patent under Reexamination	
	10/817,196		JAIN ET AL.	
	Examiner		Art Unit	
	David Q. Nguyen		2681	

ISSUE CLASSIFICATION											
ORIGINAL					CROSS REFERENCE(S)						
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
455		411		455	410	412.1	432.1	432.2	432.3	433	435.1
INTERNATIONAL CLASSIFICATION				455	436	439					
H	O	4	M	1/68	370	337					
				/	340	5.21	5.74				
				/	370	247	270				
				/							
				/							
<i>Nguyen</i> 04/18/06 (Assistant Examiner) (Date)					<i>Joseph Feild</i> JOSEPH FEILD SUPERVISORY PATENT EXAMINER (Primary Examiner) 5/1/06					Total Claims Allowed: 17	
<i>Joseph Feild</i> 05/02/06 (Legal Instruments Examiner) (Date)										O.G. Print Claim(s) 1	O.G. Print Fig. 1

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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5	5	35	65	95	125	155	185
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7	7	37	67	97	127	157	187
8	8	38	68	98	128	158	188
9	9	39	69	99	129	159	189
10	10	40	70	100	130	160	190
11	11	41	71	101	131	161	191
12	12	42	72	102	132	162	192
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25	25	55	85	115	145	175	205
26	26	56	86	116	146	176	206
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